



Contribution of X-ray Fluorescence Techniques in Cultural Heritage Materials Characterisation

Guest Editors:

Dr. Anna Galli

Dipartimento di Scienza dei
Materiali, University of Milano-
Bicocca, Via. R. Cozzi 55, I-20125
Milan, Italy

Dr. Letizia Bonizzoni

Dipartimento di Fisica, Università
degli Studi di Milano, 20122
Milano, Italy

Deadline for manuscript
submissions:

closed (31 October 2021)

Message from the Guest Editors

This Special Issue is intended to collect papers dealing with any of the analytical techniques related to XRF spectroscopy appropriate for applications to Cultural Heritage materials. Paper subjects can range from instrumentation and technical developments to case studies requiring methodological innovations, from theoretical simulations to new data handling. All the variations of XRF spectroscopy will be considered: portable or mapping spectrometers, synchrotron based XRF, total reflection or grazing techniques, and synergical association with any other non-destructive analytical techniques.

Keywords

- XRF
- pXRF
- Micro XRF
- XRF mapping
- Synchrotron based XRF
- Cultural heritage materials
- Archaeometry





an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), Inspec, CAPlus / SciFinder, and other databases.

Journal Rank: JCR - Q1 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)

Contact Us

Applied Sciences Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland

Tel: +41 61 683 77 34
www.mdpi.com

mdpi.com/journal/applsci
applsci@mdpi.com
[X@Applsci](#)